

ISSN 2005-8705
PROCEEDINGS OF APLS 2016
(Special Edition of ALTA 2016, OSK
Volume 15, Issue 1, May 2016)

May 10-14, 2016
Seogwipo KAL Hotel
Jeju Island, Korea

APLS 2016

The 10th Asia-Pacific Laser Symposium

Jointly organized with the 15th Advanced Lasers and Their Applications

Organized by

– Optical Society of Korea

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Thursday, May 12

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Ablation depth control on transparent electrode using beam shaped femtosecond laser

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Abstract—We report on the ablation depth control with a resolution of 40 nm on indium tin oxide (ITO) thin film using a square beam shaped femtosecond (190 fs) laser ($\lambda_p = 1030$ nm).

I. INTRODUCTION AND BACKGROUND

Indium tin oxide (ITO) is the widely used as transparent conducting oxide (TCO) for fabrication of optoelectronic products such as flat-panel displays, touch panels, solar cells and organic light emitting devices (OLEDs) because of their high electrical conductivity and high transmittance in the visible and near IR (infrared) wavelength range [1]. In order to enhance optical transmittance for cutting back power consumption as well as reducing the resistance to improve electrical conductivity of ITO thin films, finding ways to control micromachining depth of ITO thin films deposited on substrates as glass or PET is highly significant role in the field of displays fabrication and assembly [2]. Though various techniques have been developed to patterning ITO thin films, the current methods include photolithography with wet etching. However, it has to require multiple process and too costly equipment as well as environment-unfriendly by toxic chemicals. Therefore, it is necessary to develop direct patterning strategy without patterning mask to control forming depth with well-defined morphology on ITO thin films.

Information of the experimental sample is shown in Fig. 1. ITO thin films with a thickness of approximately 150 nm and a transmissivity of 90.5 % were deposited on the glass substrates using a DC magnetron sputtering system. Fig.2 presents the experimental setup schematically. In this experiments, The ITO thin films were patterned using a commercial regenerative amplified mode-locked Yb:KGW laser with a central wavelength of 1030 nm, a pulse width of ~200 fs, a repetition rate of 30kHz, and maximum pulse energy of 66uJ. As shown in the Fig. 2, a Gaussian laser beam was passed through slit, Gaussian beam was shaped to quasi-flat top beam by slit. The shaped quasi-flat top beam had square type shape. In this present, the following laser ablation experiments are conducted to control ablation depth of ITO thin film on the glass substrate using shaped quasi-flat top beam, and to accomplish selective ablation between ITO thin film and glass substrate.

II. RESULTS

In this study, experiment has described single pulse control using shaped quasi-flat top beam by slit for controlling ablation

depth. Fig. 3 shows the optical microscope images of morphology on the ablated ITO thin film. The damage threshold both ITO thin film and glass substrate were measured in order to avoid damage on the glass, so that conduct selective ablation successfully. We selectively controlled forming depth and removed the ITO thin films with thickness 150nm on glass substrates. In particular, we observed when the 6 pulses number at 2.8TW/cm².

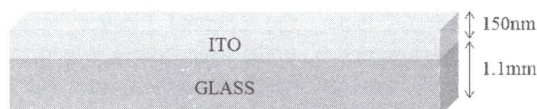


Figure1. Sample information

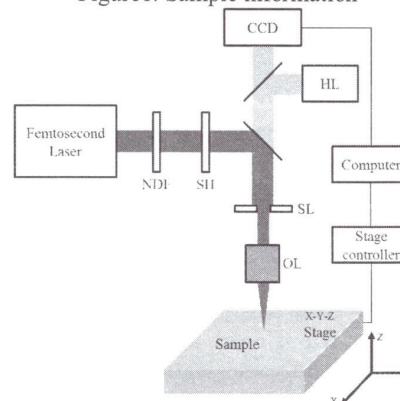


Figure2. Schematic diagram of femtosecond laser system with slit

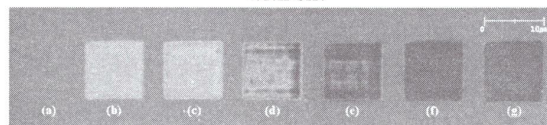


Figure3. Optical microscopic views of morphology on ablated ITO film by NIR femtosecond laser irradiation with each different pulse shots; (a) 0 shots (b) 1 shot (c) 2 shots (d) 3 shots (e) 4 shots (f) 5 shots (g) 6 shots

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